## Notice of References Cited Application/Control No. 10/791,299 Examiner Justin Y. Lee Applicant(s)/Patent Under Reexamination HOSMER ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0107830	08-2002	Nanja, Murthi	707/1
*	В	US-2004/0176085	09-2004	Phillips et al.	455/418
*	С	US-2004/0199635	10-2004	Ta et al.	709/226
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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## **NON-PATENT DOCUMENTS**

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